

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20181004003.1 Transfer of select VIP1P devices from GFAB to DFAB Wafer Fab site Change Notification / Sample Request

Date: October 09, 2018 **To:** PREMIER FARNELL PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

PCN Team SC Business Services

20181004003.1 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE

CUSTOMER PART NUMBER

LP3878MR-ADJ/NOPB LP3878MRX-ADJ/NOPB LP3878SD-ADJ/NOPB null null null

Technical details of this Product Change follow on the next page(s).

PCN Number: 201		181004003.1		PCN Date:		:	Oct 9, 2018		
Title: Transfer of select \		VIP1P devices from GFAB to DFAB (DL-LIN) Wafer Fab site							
Customer Contact:			PCN Manager		Dept:			Quality Services	
Proposed 1 st Ship Date:			Jan 9, 2019 Estimated S			•		Date provided at sample request.	
Change Type:									
Assembly Site			Assembly Process			Assembly Materials			
Design			Electrical Specification				Me	chanical Specification	
Test Site			Packing/Shipping/Labeling		J		Tes	st Process	
☐ Wafer Bump Site			Wafer Bump Material				Wafer Bump Process		
			☐ Wafer Fab Materials				Wa	ifer Fab Process	
	Part number change								
PCN Details									

Description of Change:

This change notification is to announce the transfer of select VIP1P devices from GFAB to the DFAB (DL-LIN) Wafer Fab site for the selected devices listed in the "Product Affected" section.

Curi	rent Fab Site	9	New Fab Site		
Current Fab Process Site		Wafer Diameter	New Fab Site	Process Wafer Diameter	
GFAB8	VIP1P	200 mm	DL-LIN	VIP1P	200 mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Greenock, Scotland (GFAB) Wafer Fab site closure

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

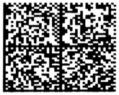
Current Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
GFAB8	GF8	GBR	Greenock

New Fab Site:

New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DL-LIN	DLN	USA	Dallas

Sample product shipping label (not actual product label)





(1P) SN74LS07NSR (D) 0336 31T)LOT: 3959047MLA 4W) TKY(1T) 7523483S12 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MA

Product Affected:

LP3878MR-ADJ	LP3878MRX-ADJ/NOPB	LP3878SD-ADJ/NOPB	LP3878SDX-ADJ/NOPB
LP3878MR-ADJ/NOPB	LP3878SD-ADJ/J7002766		

Qualification Report

DFAB Process qualification VIP1P - LP3878MRX-ADJ/NOPB Approve Date 27-Sept-2018

Product Attributes

Attributes	Qual Device: LP3878MRX- ADJ/NOPB	QBS Device: LP2985AIM5-5.0/NOPB
Assembly Site	TIEM	TIEM
Package Family	HSOIC	SOT-23
Flammability Rating	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DFAB-DALLAS	DFAB-DALLAS
Wafer Process	VIP1P	VIP1P

⁻ Qual Devices qualified at LEVEL3-260CG: LP2985AIM5-5.0/NOPB-CL, LP2985AIM5-5.0/NOPB-TL

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: LP3878MRX- ADJ/NOPB	QBS Device: LP2985AIM5- 5.0/NOPB
AC	Autoclave 121C	96 Hours	-	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	Pass
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0
HBM	ESD - HBM	2500 V	-	3/9/0
CDM	ESD - CDM	1000 V	-	3/9/0
HTOL	Life Test, 125C	1000 Hours	1/77/0	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	3/231/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass
MQ	Manufacturability (Wafer Fab)	(per mfg. Site specification)	Pass	Pass
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com